

Search Notes

Application/Control No.

10/510,704

Examiner

John S. Chu

Applicant(s)/Patent under
Reexamination

HATANAKA ET AL.

Art Unit

1752

SEARCHED

Class	Subclass	Date	Examiner
430	191	10/2005	jlc
430	192		
430	193		
430	165		
430	280.1		
430	326		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
430	190,191	10/2005	jlc
430	192		
430	193		
430/280.1,326			

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST SEARCH UPDATED	10/2005	jlc